

RT-70V SERIES CONTACT TYPE RESISTIVITY/SHEET RESISTANCE MEASUREMENT

RT-70V



- Single point, contact type
- 4-Point Measurement method
- Measurement Range:
 - ✓ Resistivity ($\Omega \cdot \text{cm}$): 1u to 3M
 - ✓ Sheet Resistance (Ω/sq): 5m to 10M
- Sample Size: Dependent on measurement stage options
- Thickness input with easy JOG dial operation
- Tester self-test function/Auto change-over measurement range function

MEASUREMENT STAGE OPTIONS:



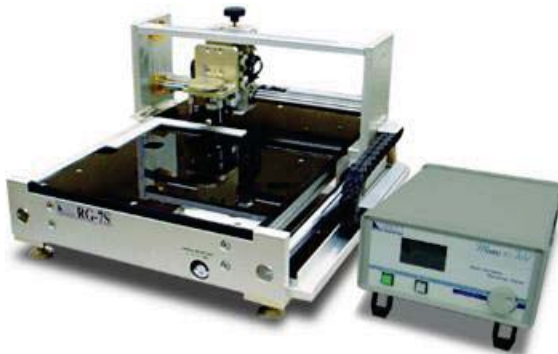
RG-7C

- Electronics control of Probe Up-Down
- **Sample Size:** 300mm diameter, 10mm thickness



RG-5

- Manual Probe Up-Down by handle
- **Sample Size:** 200mm diameter, 10mm thickness



RG-7S

- Electronics control of probe up-down
- Glass or Film sample using X-Y universal stage
- **Sample Size:** 500mm x 500mm, 10mm thickness



TS-7D

- Hand held 4-point probe measurement
 - Optional stage plate
 - **Sample Size (Minimum):** 20mm

APPLICABLE MATERIALS

- Semiconductor materials, Solar-cell materials (Silicon, Polysilicon, SiC etc)
- Functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
- Conductive thin film (Metal, ITO etc)
- Diffused sample (or layer)
- Silicon-related thin films (LTPS etc)